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e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other			

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AA	4,835,740		Sato						
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AC	4,761,384		Neppl						
AD			Mitchell		I		T -		
AE	6,043,114		Kawagoe						
AF	4,564,416		Homma, et al.						
AG	4,684,971	8-87	Payne, et al.						
AH	5,237,188		Iwai, et al.						
AI	5,396,093		Lu						
AJ	5,508,540		Ikeda, et al.		L				
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AN	0550021	7-85	Europe						
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AU	Wolf, S., "S	ilicon Proces	ing for the VLSI Era Vol.	1", ppg	. 64-65.				
AV	Ghandhi, S.	, "VLSI Fabr	ication Principles Silicon a	ınd Gal	ium Ars	enide", ppg	<u>, 735-7, </u>	38.	
AW	Yamaguchi with 16-GH 36, No. 5, p	et al., "Proce z f(t) double pg. 890-896.	ss integration and device p Poly-Bipolar devices", IEI	erform EE Tran	ance of a sactions	submicror on Electror	neter Bi n Device	CMOS s, Vol.	
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	AA	5,216,269	6-93	Middlehoek, et al.				†		
	AB	4,525,920	7-85	Jacobs, et al.				1		
	AC	4,717,686	1-88	Jacobs, et al.				1		
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